

Product Change Notification - JAON-22CQBF728

Date:

25 May 2020

Product Category:

8-bit Microcontrollers

Affected CPNs:



Notification subject:

CCB 3702.003 and 3702.004 Final Notice: Qualification of palladium coated copper with gold flash (CuPdAu) bond wire, 8600 die attach and G700LTD mold compound material for selected ATML AT90CAN64, AT90CAN128, AT90PWM81xx and ATMEGA168PA device families available in 32L VQFN (5x5x0.9mm) and 64L VQFN (9x9x0.9mm) packages at NSEB assembly site.

Notification text:

PCN Status:

Final notification

PCN Type:

Manufacturing Change

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:

Qualification of palladium coated copper with gold flash (CuPdAu) bond wire, 8600 die attach and G700LTD mold compound material for selected ATML AT90CAN64, AT90CAN128, AT90PWM81xx and ATMEGA168PA device families available in 32L VQFN (5x5x0.9mm) and 64L VQFN (9x9x0.9mm) packages at NSEB assembly site.

Pre Change:

For 32L VQFN: Using gold (Au) bond wire, 8600 die attach, G770HCD mold compound and A194 lead frame material.

For 64L VQFN: Using gold (Au) bond wire, 8200T die attach, G770HCD mold compound and EFTEC 64T lead frame material.

Post Change:

For both 32L and 64L VQFN: Using palladium coated copper with gold flash (CuPdAu) bond wire, 8600 die attach, G700LTD mold compound and EFTEC 64T lead frame material.

Pre and Post Change Summary:

	Change Summary	Ï	
		Pre Change	Post Change
		UTAC Thai Limited LTD.	UTAC Thai Limited LTD.
Assembly Sit	e		
_		(NSEB)	(NSEB)
Wire material		Au	CuPdAu
Die attach	64L VQFN	8200T	8600
material	32L VQFN	8600	8000
Molding compound material		G770HCD	G700LTD
Lead frame	64L VQFN	EFTEC 64T	EFTEC 64T
material	32L VQFN	A194	LI 120 041

Impacts to Data Sheet:

None

Change Impact:

None



Reason for Change:

To improve productivity by qualifying palladium coated copper with gold flash (CuPdAu) bond wire.

Change Implementation Status:

In Progress

Estimated First Ship Date:

July 10, 2020 (date code: 2028)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Time Table Summary:

		May 2020			->		Jı	uly 202	20		
Workweek	18	19	20	21	22	1	27	28	29	30	31
Qual Report Availability					X						
Final PCN Issue Date					Χ						
Estimated Implementation											
Date								^			

Method to Identify Change:

Traceability code

Qualification Report:

Please open the attachments included with this PCN labeled as PCN_#_Qual Report.

Revision History:

May 25, 2020: Issued final notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):

PCN JAON-22CQBF728 Qual Report.pdf

Please contact your local <u>Microchip sales office</u> with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to receive Microchip PCNs via email please register for our PCN email service at our PCN home page select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the PCN FAQ section.

If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

JAON-22CQBF728 - CCB 3702.003 and 3702.004 Final Notice: Qualification of palladium coated copper with gold flash (CuPdAu) bond wire, 8600 die attach and G700LTD mold compound material for selected ATML AT90CAN64, AT90CAN128, AT90PWM81xx and ATMEGA168PA device families available in 32L VQFN (5x5x0.9mm) and 64L VQFN (9x9x0.9mm) packages at NSEB assembly site.

Affected Catalog Part Numbers (CPN)

ATMEGA168PA-MU

ATMEGA168PA-MUR

AT90PWM81EP-16MN

AT90PWM81OS-B16MNR

AT90CAN64-16MU

AT90CAN64-16MU-HCM

AT90CAN64-16MUR

AT90CAN128-16MU

AT90CAN128-16MUR

Date: Monday, May 25, 2020



QUALIFICATION REPORT SUMMARY

RELIABILITY LABORATORY

PCN #: JAON-22CQBF728

Date December 19, 2019

Qualification of palladium coated copper with gold flash (CuPdAu) bond wire, 8600 die attach and G700LTD mold compound material for selected Atmel products available in 64L VQFN package at NSEB assembly site. The selected ATML AT90CAN64, AT90CAN128, AT90PWM81xx and ATMEGA168PA device families available in 32L VQFN (5x5x0.9mm) and 64L VQFN (9x9x0.9mm) packages will qualify by similarity. This is an Automotive Grade 1 qualification.



Purpose:

Qualification of palladium coated copper with gold flash (CuPdAu) bond wire, 8600 die attach and G700LTD mold compound material for selected Atmel products available in 64L VQFN package at NSEB assembly site. The selected ATML AT90CAN64, AT90CAN128, AT90PWM81xx and ATMEGA168PA device families available in 32L VQFN (5x5x0.9mm) and 64L VQFN (9x9x0.9mm) packages will qualify by similarity. This is an Automotive Grade 1 qualification.

	Assembly site	NSEB				
	BD Number	BDM-002057B				
်င်	MP Code (MPC)	355T7YTPBC01				
Misc.	Part Number (CPN)	AT90CAN128-15MZ				
	Qual ID	QTP3827 Rev. A				
	CCB No.	3702, 3702.001, 3702.003 and 3702.004				
	Paddle size	6.7x6.7				
	Material	EFTEC 64T				
	Surface	Non rough				
me	Treatment	Yes (In house roughening)				
Lead-Frame	Process	Etched				
<u>-</u>	Lead-lock	Yes				
ea	Part Number	FR0691				
,	Lead Plating	Selective Ag (Finger only)				
	Strip Size	70x250mm				
	Strip Density	120 unit/strip				
Bond Wire	Material	CuPdAu				
<u>Die</u> Attach	Part Number	8600				
D Att	Conductive	Conductive				
MC	Part Number	G700LTD				
(DI	PKG Type	QFN				
PKG	Pin/Ball Count	64				
<u> </u>	PKG width/size	9x9x0.85				



Manufacturing Information:

Assembly Lot No.
NSEB200700001.000
NSEB200700002.000
NSEB200700002.000

Result	Pass	Fail	

vQFN Matt Sn 9x9 64L Package with PdCuAu wire in Utac for DNP lead frame is qualified **Automotive Grade 1** and Passed Moisture/ Reflow Sensitivity Classification Level 3 at 260°C reflow temperature per IPC/JEDEC J-STD-020D standard. No delaminations were observed on all the units.

	PACKAGE QUALIFIC	CATION	IREF	PORT		
Test Number (Reference)	Test Condition	Standard / Method	Qty. (Acc.)	Def/SS	Result	Remarks
Precondition Prior Perform Reliability Tests(At MSL	Electrical Test: +25°C, +85°C, +125°C System:	JESD22- A113 231 units of 3 Lots	693(0)	0/693	Pass	
Level 3)	Bake 150°C, 24 hrs System:	IDO/IED	693(0			
	30°C/60%RH Moisture Soak 192 hrs. System: Climats Excal 5423-HE	IPC/JED EC J- STD- 020E	693(0)			
	3x Convection-Reflow 265°C max System: Mancorp CR.5000F		693(0)	0/693	Pass	
	Electrical Test :+25°C, +85°C, +125°C System:		693(0)	0/693	Pass	

	PACKAGE QUALIF	ICATION	REP	PORT		
Test Number (Reference)	Test Condition	Standard / Method	Qty. (Acc.)	Def/SS	Result	Remarks
Temp Cycle Parts had been pre-conditioned at 260°C	Stress Condition: (Standard) -65°C to +150°C, 500 Cycles System:	JESD22- A104 77 units of 3 Lots	231(0)			
	Electrical Test :+85°C, +125°C System: Mav VT		231(0)	0/231	Pass	
	Bond Strength: Wire /Stitch Pull Bond Shear		15(0)	0/15	Pass	
	Stress Condition: (Standard) -65°C to +150°C, 1000 Cycles		213(0)	0/213	Pass	
	Electrical Test: +85°C, +125°C		213(0)	0/213	Pass	
	System: Mav VT					
	Bond Strength: Wire /Stitch Pull Bond Shear		15(0)	0/15	Pass	

PACKAGE QUALIFICATION REPORT								
Test Number (Reference)	Test Condition	Standard / Method	Qty. (Acc.)	Def/SS	Result	Remarks		
Parts had been pre-conditioned at 260°C	Stress Condition: (Standard) +130°C/85%RH, 96hrs. Bias Volt: 5.5 Volts System:	JESD22- A104 77 units of 3 Lots	231(0)					
	Electrical Test: +25°C, +85°C, +125°C System: Mav VT		231(0)	0/231	Pass			
	Bond Strength: Wire /Stitch Pull Bond Shear		15(0)	0/15	Pass			
	Stress Condition: (Standard) +130°C/85%RH,192hrs. Bias Volt: 5.5 V System: VOTSCH VT 7012 S2		213(0)					
	Electrical Test :+25°C, +85°C, +125°C System: Mav VT		213(0)	0/213	Pass			
	Bond Strength: Wire /Stitch Pull Bond Shear		15(0)	0/15	Pass			

	PACKAGE QUALIFIC	ATION	REP	PORT		
Test Number	Test Condition S		Qty.	Def/SS.	Result	Remarks
(Reference)		Method	(Acc.)			
UnBiased HAST Parts had been pre-	Stress Condition: (Standard) +130°C/85%RH, 96hrs	JESD22- A104	231(0)			
-	System:	77 units of 3 Lots				
	Electrical Test :+25°C		231(0)	0/213	Pass	
	System: Mav VT					
	Stress Condition: (Standard) +130°C/85%RH,192hrs. Bias Volt: 5.5 V		231(0)			
	System: VOTSCH VT 7012 S2					
	Electrical Test :+25°C		231(0)	0/231	Pass	
	System: Mav VT					
High Temperature Storage Life	Stress Condition: (Standard) Bake 175°C, 500 hrs	JESD22- A104	135(0)			
	System: VOTSCH VT 7012 S2	77 units of 3 Lots				
	Electrical Test :+25°C, +85°C, +125°C		135(0)	0/135	Pass	
	System: Mav VT					
	Stress Condition: (Standard) Bake 175°C, 1000 hrs		132(0)			
	System: VOTSCH VT 7012 S2					
	Electrical Test: +25°C, +85°C, +125°C		132(0)	0/132	Pass	
	System: Mav VT					

PACKAGE QUALIFICATION REPORT								
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks		
Bond Strength Data Assembly		M2011.8 MIL-STD- 883	35(0)	0/35	Pass			
	Bond Shear	330	35(0)	0/35	Pass			